







TCAN1044A-Q1, TCAN1044AV-Q1 SLLSFJ3C - FEBRUARY 2021 - REVISED DECEMBER 2021

TCAN1044A-Q1 and TCAN1044AV-Q1 Automotive Fault-Protected CAN FD Transceiver with Standby mode

1 Features

TEXAS

INSTRUMENTS

- AEC-Q100 (Grade 1) Qualified for automotive applications
- Meets the requirements of ISO 11898-2:2016 physical layer standard
- Functional Safety-Capable
 - Documentation available to aid in functional safety system design
- Support of classical CAN and optimized CAN FD performance at 2, 5, and 8 Mbps
 - Short and symmetrical propagation delays for enhanced timing margin
- TCAN1044AV I/O voltage range supports 1.7 V to 5.5 V
- Support for 12-V and 24-V battery applications
- Receiver common mode input voltage: ±12 V
- Protection features:
 - Bus fault protection: ±58 V
 - Undervoltage protection
 - TXD-dominant time-out (DTO)
 - Data rates down to 9.2 kbps
 - Thermal-shutdown protection (TSD)
- Operating modes: ٠
 - Normal mode
 - Low power standby mode supporting remote wake-up request
- Optimized behavior when unpowered
 - Bus and logic pins are high impedance (no load to operating bus or application)
 - Hot-plug capable: power up/down glitch-free operation on bus and RXD output
- 8-Pin SOIC, small footprint SOT-23 and leadless VSON-8 package with improved automated optical inspection (AOI) capability

2 Applications

- Automotive and transportation
 - Body control modules
 - Automotive gateway
 - Advanced driver assistance system (ADAS)
 - Infotainment

3 Description

The TCAN1044A-Q1 and TCAN1044AV-Q1 are high speed controller area network (CAN) transceivers that meets the physical layer requirements of the ISO 11898-2:2016 high-speed CAN specification.

The transceivers have certified electromagnetic compatibility (EMC) operation making it an ideal choice for classical CAN and CAN FD networks up to 5 megabits per second (Mbps). Up to 8 Mbps operation in simpler networks is possible with these devices. The TCAN1044AV-Q1 includes internal logic level translation via the V_{IO} pin to allow for interfacing the transceiver I/O's directly to 1.8-V, 2.5-V, 3.3-V, or 5-V logic levels. The transceiver supports a low-power standby mode and wake over CAN which is compliant to the ISO 11898-2:2016 defined wake-up pattern (WUP).

The transceivers also include thermal-shutdown (TSD). TXD-dominant time-out (DTO), supply undervoltage detection, and ±58-V bus fault protection. The devices have defined fail-safe behavior in supply undervoltage or floating pin scenarios. These transceivers are not only available in industry-standard SOIC-8 and VSON-8 packages, but also have a space-saving small footprint SOT-23 package option.

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
TCAN1044A-Q1 TCAN1044AV-Q1	SOIC (D)	4.90 mm x 3.91 mm
	VSON (DRB)	3.00 mm x 3.00 mm
	SOT-23 (DDF)	2.90 mm x 1.60 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Schematic



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision B (October 2021) to Revision C (December 2021)	Page
•	Changed I _{CC} (mA) to I _{CC} (μA) in Figure 7-3	10
	Changed I_{IO} (mA) to I_{IO} (µA) in Figure 7-4	

С	Changes from Revision A (July 2021) to Revision B (October 2021) Pa		
•	Deleted Product Preview from the D and DDF packages in the Device Information table	1	

С	Changes from Revision * (February 2021) to Revision A (July 2021)	
•	Changed the document status from: Advanced Information to: Production data	1



5 Device Comparison

Part Number	Low Voltage I/O Logic Support on Pin 5	Pin 8 Mode Selection
TCAN1044A-Q1	No	Low Power Standby Mode with Remote
TCAN1044AV-Q1	Yes	Wake

Table 5-1. Device Comparison Table

6 Pin Configuration and Functions









Figure 6-3. DRB Package, 8-Pin VSON, Top View

Table 6-1. Pin Functions

Pins		Tuno	Description	
Name	No.	Туре	Description	
TXD	1	Digital Input	CAN transmit data input; integrated pull-up	
GND	2	GND	Ground connection	
V _{CC}	3	Supply	5-V supply voltage	
RXD 4 Digital Output CAN receive data output, tri-stated when device powered off		CAN receive data output, tri-stated when device powered off		
NC	_	Not internally connected; Devices without V _{IO}		
V _{IO} 5		Supply	I/O supply voltage for devices with suffix 'V'	
CANL 6		Bus IO	Low-level CAN bus input/output line	
CANH	7	Bus IO	High-level CAN bus input/output line	
STB 8		Digital Input	Standby input for mode control; integrated pull-up	
Thermal Pad (VSON only)		_	Connect the thermal pad to any internal PCB ground plane using multiple vias for optimal thermal performance.	



7 Specifications

7.1 Absolute Maximum Ratings

(1) (2)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	-0.3	6	V
V _{IO}	Supply voltage I/O level shifter	-0.3	6	V
V _{BUS}	CAN Bus I/O voltage	-58	58	V
V _{DIFF}	Max differential voltage between CANH and CANL	-45	45	V
V _{Logic_Input}	Logic input terminal voltage	-0.3	6	V
V _{RXD}	RXD output terminal voltage range	-0.3	6	V
I _{O(RXD)}	RXD output current	-8	8	mA
TJ	Junction temperature	-40	165	°C
T _{STG}	Storage temperature	-65	150	°C

(1) Operation outside the Absolute Maximum Ratings may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Conditions. If used outside the Recommended Operating Conditions but within the Absolute Maximum Ratings, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

(2) All voltage values, except differential I/O bus voltages, are with respect to ground terminal.

7.2 ESD Ratings

		VALUE	UNIT		
			HBM classification level 3A for all pins	±4000	V
V _{ESD}	Electrostatic discharge globa	HBM classification level 3B for global pins CANH and CANL with respect to GND	±10000	V	
				±750	V

(1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 ESD Ratings - IEC Specifications

				VALUE	UNIT
V _{ESD}			Unpowered contact discharge per ISO 10605 ⁽¹⁾	±8000	V
	System level Electrostatic discharge		SAE J2962-2 per ISO 10605 Powered Contact Discharge (2)	±8000	v
		CAN bus terminals to GND	SAE J2962-2 per ISO 10605 Powered Air Discharge ⁽²⁾	±15000	V
			Pulse 1	-100	V
	Transient veltage per ISO 7627 2(3)		Pulse 2a	75	V
V _{Tran}	Transient voltage per ISO 7637-2 ⁽³⁾		Pulse 3a	-150	V
			Pulse 3b	100	V
	Transient voltage per ISO 7637-3 ⁽⁴⁾		DCC slow transient pulse	±30	V

(1) Tested according to IEC 62228-3:2019 CAN Transceivers.

(2) Results given here are specific to the SAE J2962-2 Communication Transceivers Qualification Requirements - CAN. Testing performed by OEM approved independent third party, EMC report available upon request.

- (3) Tested according to IEC 62228-3:2019 CAN Transceivers.
- (4) Tested according to SAE J2962-2.

7.4 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	V



7.4 Recommended Operating Conditions (continued)

		MIN	NOM MAX	UNIT
V _{IO}	Supply voltage for I/O level shifter	1.7	5.5	V
I _{OH(RXD)}	RXD terminal high-level output current, Devices with VIO	-1.5		mA
I _{OL(RXD)}	RXD terminal low-level output current, Devices with V_{IO}		1.5	mA
I _{OH(RXD)}	RXD terminal high-level output current, Devices without V_{IO}	-2		mA
I _{OL(RXD)}	RXD terminal low-level output current, Devices without V_{IO}		2	mA
Tj	Operating junction temperature	-40	150	°C

7.5 Thermal Characteristics

	THERMAL METRIC ⁽¹⁾		TCAN1044Ax-Q1		UNIT
		D (SOIC)	DDF (SOT)	DRB (VSON)	UNIT
R _{θJA}	Junction-to-ambient thermal resistance	127.5	122	55.2	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	67.6	63	62.4	°C/W
R _{θJB}	Junction-to-board thermal resistance	70.9	42.4	27.5	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	19.3	2.4	2.3	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	70.2	42.2	27.4	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance			11.5	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

7.6 Supply Characteristics

Over recommended operating conditions with $T_J = -40^{\circ}C$ to 150°C (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		Dominant	$\begin{split} \text{STB} &= 0 \text{ V}, \text{TXD} = 0 \text{ V} \\ \text{R}_{\text{L}} &= 60 \Omega, C_{\text{L}} = \text{open} \\ \text{See Figure 8-1} \end{split}$		45	70	mA
	Supply current	Dominant	$\begin{split} \text{STB} &= 0 \text{ V}, \text{TXD} = 0 \text{ V} \\ \text{R}_{\text{L}} &= 50 \Omega, C_{\text{L}} = \text{open} \\ \text{See Figure 8-1} \end{split}$		49	80	mA
	Normal mode	Recessive	$\begin{array}{l} \text{STB = 0 V, TXD = V_{CC} \text{ or } V_{IO} \\ \text{R}_{L} = 50 \ \Omega, \ \text{C}_{L} = \text{open} \\ \text{See Figure 8-1} \end{array}$		4.5	7.5	mA
I _{CC}	Dominant with bus fault	$\begin{split} \text{STB} &= 0 \text{ V}, \text{TXD} = 0 \text{ V} \\ \text{CANH} &= \text{CANL} = \pm 25 \text{ V} \\ \text{R}_{\text{L}} &= \text{open}, \text{ C}_{\text{L}} = \text{open} \\ \text{See Figure 8-1} \end{split}$			130	mA	
	Supply current Standby mode Devices with V _{IO}		$\begin{array}{l} \text{STB} = \text{TXD} = \text{V}_{\text{IO}} \\ \text{R}_{\text{L}} = 50 \ \Omega, \ \text{C}_{\text{L}} = \text{open} \\ \text{See Figure 8-1} \end{array}$			1.5	μA
	Supply current Standby mode Devices without V _{IO}		$\begin{array}{l} \text{STB} = \text{TXD} = \text{V}_{\text{CC}} \\ \text{R}_{\text{L}} = 50 \ \Omega, \ \text{C}_{\text{L}} = \text{open} \\ \text{See Figure 8-1} \end{array}$			15	μA
	I/O supply current Normal mode	Dominant	STB = 0 V, TXD = 0 V RXD floating		125	300	μA
I _{IO}	I/O supply current Normal mode	Recessive	STB = 0 V, TXD = 0 V RXD floating		25	48	μA
	I/O supply current Standby mode		STB = V _{IO,} TXD = 0 V RXD floating		8.5	14	μA
111/	Rising undervoltage detecti	on on V _{CC} for prote	ected mode		4.2	4.4	V
UV _{CC}	Falling undervoltage detect	ion on V _{CC} for prot	ected mode	3.5	4	4.25	V
V _{HYS(UVCC)}	Hysteresis voltage on UV _{CC}	;			200		mV
1.11.7	Rising undervoltage detecti	on on V _{IO} (Devices	s with V _{IO})		1.56	1.65	V
UV _{VIO}	Falling undervoltage detect	ion on V _{IO} (Device	s with V _{IO})	1.4	1.51	1.59	V
V _{HYS(UVIO)}	Hysteresis voltage on UV _{IO}				40		mV



7.7 Dissipation Ratings

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	C _{L_RXD} = 15 pF TXD input = 2.5 MHz 50% duty cycle square wave	$C_{L RXD} = 15 \text{ pF}$ TXD input = 250 kHz 50% duty cycle square		95		mW
		$C_{L RXD} = 15 \text{ pF}$ TXD input = 250 kHz 50% duty cycle square		95		mW
		C _{L_RXD} = 15 pF TXD input = 250 kHz 50% duty cycle square		95		mW
PD		TXD input = 2.5 MHz 50% duty cycle square		120		mW
		TXD input = 2.5 MHz 50% duty cycle square		120		mW
		$C_{L_{RXD}} = 15 \text{ pF}$ TXD input = 2.5 MHz 50% duty cycle square		120		mW
T _{TSD}	Thermal shutdown temperature		175	195	210	°C
T _{TSD(HYS)}	Thermal shutdown hysteresis			12		U

7.8 Electrical Characteristics

Over recommended operating conditions with $T_J = -40^{\circ}C$ to $150^{\circ}C$ (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Driver Elec	trical Characteristics						
	Dominant output voltage		2.75		4.5	V	
V _{O(DOM)}	Normal mode	CANL	$50 \ \Omega \le R_L \le 65 \ \Omega, C_L = open, R_{CM} = open$ See Figure 8-2 and Figure 9-3	0.5		2.25	V
V _{O(REC)}	Recessive output voltage Normal mode	CANH and CANL	$\begin{array}{l} \text{STB = 0 V, TXD = V_{\text{IO}} \\ \text{R}_{\text{L}} = \text{open (no load), R}_{\text{CM}} = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{array}$	2	0.5 V _{CC}	3	v
V _{SYM}	Driver symmetry (V _{O(CANH)} + V _{O(CANL)})/V _{CC}		$\label{eq:stars} \begin{array}{l} \text{STB = 0 V, TXD = 250 kHz, 1 MHz, 2.5} \\ \text{MHz} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{SPLIT}} = 4.7 \ \text{nF}, \ \text{C}_{\text{L}} = \text{open}, \\ \text{R}_{\text{CM}} = \text{open} \\ \text{See Figure 8-2 and Figure 10-2} \end{array}$	0.9		1.1	V/V
V _{SYM_DC}	DC output symmetry (V _{CC} - V _{O(CANH)} - V _{O(CANL)})		$\begin{split} & \text{STB = 0 V} \\ & \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = \text{open} \\ & \text{See Figure 8-2 and Figure 9-3} \end{split}$	-400		400	mV
			$\begin{array}{l} \text{STB = 0 V, TXD = 0 V} \\ \text{50 } \Omega \leq \text{R}_{\text{L}} \leq \text{65 } \Omega, \text{ C}_{\text{L}} = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{array}$	1.5		3	v
V _{OD(DOM)}	Differential output voltage Normal mode Dominant	$\begin{array}{l} \text{STB = 0 V, TXD = 0 V} \\ \text{45 } \Omega \leq R_L \leq 70 \ \Omega, \ C_L = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{array}$	1.4		3.3	v	
			$\begin{split} \text{STB = 0 V, TXD = 0 V} \\ \text{R}_{\text{L}} = 2240 \ \Omega, \ \text{C}_{\text{L}} = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{split}$	1.5		5	v
V	Differential output voltage Normal mode	CANH - CANL	$\begin{array}{l} \text{STB = 0 V, TXD = V_{\text{IO}} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{array}$	-120		12	mV
V _{OD(REC)}	Recessive		$\begin{array}{l} \text{STB = 0 V, TXD = V_{\text{IO}} \\ \text{R}_{\text{L}} = \text{open, } \text{C}_{\text{L}} = \text{open} \\ \text{See Figure 8-2 and Figure 9-3} \end{array}$	-50		50	mV



7.8 Electrical Characteristics (continued)

Over recommended operating conditions with $T_J = -40^{\circ}C$ to 150°C (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	ТҮР	MAY	UNI
	PARAMETER	CANUL	TEST CONDITIONS		ITP	MAX	
	Bus output voltage	CANH	STB = V _{IO}	-0.1		0.1	V
V _{O(STB)}	Standby mode	CANL	R _L = open See Figure 8-2 and Figure 9-3	-0.1		0.1	V
	CANH - CANL			-0.2		0.2	V
los(ss_dom)	Short-circuit steady-state c dominant	output current,	$\begin{split} \text{STB} &= 0 \text{ V}, \text{ TXD} = 0 \text{ V} \\ \text{V}_{(\text{CANH})} &= -15 \text{ V} \text{ to } 40 \text{ V}, \text{ CANL} = \text{open} \\ \text{See Figure 8-7 and Figure 9-3} \end{split}$	-115			mA
03(33_00M)	Normal mode		$\begin{array}{l} \text{STB = 0 V, TXD = 0 V} \\ \text{V}_{(\text{CAN}_L)} = \text{-15 V to 40 V, CANH = open} \\ \text{See Figure 8-7 and Figure 9-3} \end{array}$			115	mA
los(ss_rec)	Short-circuit steady-state c recessive Normal mode	output current,	$ \begin{array}{l} \text{STB = 0 V, TXD = V_{\text{IO}} \\ -27 \text{ V} \leq \text{V}_{\text{BUS}} \leq 32 \text{ V, where } \text{V}_{\text{BUS}} = \text{CANH} \\ = \text{CANL} \\ \text{See Figure 8-7 and Figure 9-3} \end{array} $	-5		5	mA
Receiver Ele	ectrical Characteristics						
V _{IT}	Input threshold voltage Normal mode		$\begin{split} \text{STB} &= 0 \text{ V} \\ \text{-12 V} &\leq \text{V}_{\text{CM}} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{split}$	500		900	mV
V _{IT(STB)}	Input threshold Standby mode		$\begin{array}{l} \text{STB = V_{IO}} \\ \text{-12 V} \leq V_{CM} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$	400		1150	mV
V _{DOM}	Dominant state differential Normal mode	input voltage range	$\begin{array}{l} \text{STB = 0 V} \\ \text{-12 V} \leq \text{V}_{\text{CM}} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$	0.9		9	v
V _{REC}	Recessive state differentia Normal mode	l input voltage range	$\begin{array}{l} \text{STB = 0 V} \\ \text{-12 V} \leq \text{V}_{\text{CM}} \leq \text{12 V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$	-4		0.5	v
V _{DOM(STB)}	Dominant state differential Standby mode	input voltage range	$\begin{array}{l} \text{STB = V_{IO}} \\ \text{-12 V} \leq V_{CM} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$	1.15		9	v
V _{REC(STB)}	Recessive state differentia Standby mode	l input voltage range	$\begin{array}{l} \text{STB = V_{IO}} \\ \text{-12 V} \leq V_{CM} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$	-4		0.4	v
V _{HYS}	Hysteresis voltage for inpu Normal mode	t threshold	$\begin{array}{l} \text{STB = 0 V} \\ \text{-12 V} \leq V_{\text{CM}} \leq 12 \text{ V} \\ \text{See Figure 8-3 and Table 9-6} \end{array}$		115		mV
V _{CM}	Common-mode range Normal and standby mode	s	See Figure 8-3 and Table 9-6	–12		12	V
LKG(IOFF)	Unpowered bus input leak	age current	$CANH = CANL = 5 V, V_{CC} = V_{IO} = GND$			5	μA
CI	Input capacitance to groun	d (CANH or CANL)	$TXD = V_{IO} (1)$			20	pF
C _{ID}	Differential input capacitan	се				10	pF
R _{ID}	Differential input resistance	e	STB = 0 V, TXD = V _{IO} ⁽¹⁾	40		90	kΩ
R _{IN}	Single-ended input resistant (CANH or CANL)	nce	$-12 V \le V_{CM} \le 12 V$	20		45	kΩ
R _{IN(M)}	Input resistance matching $[1 - (R_{IN(CANH)} / R_{IN(CANL)})]$		$V_{(CAN_H)} = V_{(CAN_L)} = 5 V$	-1		1	%
	al (CAN Transmit Data Inpu	it)					
V _{IH}	High-level input voltage		Devices without V _{IO}	0.7 V _{CC}			V
V _{IH}	High-level input voltage		Devices with V _{IO}	0.7 V _{IO}			V
V _{IL}	Low-level input voltage		Devices without V _{IO}			$0.3 V_{CC}$	V
V _{IL}	Low-level input voltage		Devices with V _{IO}			0.3 V _{IO}	V
IH	High-level input leakage cu	urrent	$TXD = V_{CC} = V_{IO} = 5.5 \; V$	-2.5	0	1	μA
l _{IL}	Low-level input leakage cu	rrent	TXD = 0 V V _{CC} = V _{IO} = 5.5 V	-200	-100	-20	μA
	Unpowered leakage currer	nt	$TXD = 5.5 V$ $V_{CC} = V_{IO} = 0 V$	-1	0	1	μA
LKG(OFF)			ACC- AIO - 0 A				



7.8 Electrical Characteristics (continued)

Over recommended operating conditions with $T_J = -40^{\circ}C$ to 150°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{OH}	High-level output voltage	$I_{O} = -2 \text{ mA}$ Devices without V_{IO} See Figure 8-3	0.8 V _{CC}			v
V _{OH}	High-level output voltage	$I_{O} = -1.5 \text{ mA}$ Devices with V_{IO} See Figure 8-3	0.8 V _{IO}			v
V _{OL}	Low-level output voltage	$I_{O} = 2 \text{ mA}$ Devices without V_{IO} See Figure 8-3			0.2 V _{CC}	v
V _{OL}	Low-level output voltage	I _O = 1.5mA Devices with V _{IO} See Figure 8-3			0.2 V _{IO}	v
I _{LKG(OFF)}	Unpowered leakage current	RXD = 5.5 V V _{CC} = V _{IO} = 0 V	-1	0	1	μA
STB Termir	al (Standby Mode Input)					
V _{IH}	High-level input voltage	Devices without V _{IO}	0.7 V _{CC}			V
V _{IH}	High-level input voltage	Devices with V _{IO}	0.7 V _{IO}			V
V _{IL}	Low-level input voltage	Devices without V _{IO}			0.3 V _{CC}	V
V _{IL}	Low-level input voltage	Devices with V _{IO}			0.3 V _{IO}	V
I _{IH}	High-level input leakage current	V _{CC} = V _{IO} = STB = 5.5 V	-2		2	μA
IIL	Low-level input leakage current	STB = 0 V V _{CC} = V _{IO} = 5.5 V,	-20		-2	μA
I _{LKG(OFF)}	Unpowered leakage current	STB = 5.5V V _{CC} = V _{IO} = 0 V	-1	0	1	μA

(1) $V_{IO} = V_{CC}$ in non-V variants of device

7.9 Switching Characteristics

Over recommended operating conditions with $T_J = -40^{\circ}C$ to $150^{\circ}C$ (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
Device Switching Characteristics							
t _{PROP(LOOP1)}	Total loop delay Driver input (TXD) to receiver output (RXD), recessive to dominant	$ \begin{array}{l} \text{STB = 0 V, } V_{\text{IO}} = 2.8 \text{ V to } 5.5 \text{ V} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = 100 \ \text{pF}, \ \text{C}_{\text{L}(\text{RXD})} = 15 \ \text{pF} \\ \text{See Figure 8-4} \end{array} $		125	210	ns	
tprop(loop1)	Total loop delay Driver input (TXD) to receiver output (RXD), recessive to dominant	$ \begin{array}{l} \text{STB = 0 V, V_{\text{IO}} = 1.7 V} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = 100 \ \text{pF}, \ \text{C}_{\text{L}(\text{RXD})} = 15 \ \text{pF} \\ \text{See Figure 8-4} \end{array} $		165	255	ns	
t _{PROP(LOOP2)}	Total loop delay Driver input (TXD) to receiver output (RXD), dominant to recessive	$\begin{array}{l} \text{STB = 0 V, V_{\text{IO}} = 2.8 V to 5.5 V} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = 100 \ \text{pF}, \ \text{C}_{\text{L(RXD)}} = 15 \ \text{pF} \\ \text{See Figure 8-4} \end{array}$		150	210	ns	
t _{PROP(LOOP2)}	Total loop delay Driver input (TXD) to receiver output (RXD), dominant to recessive	$ \begin{array}{l} \text{STB = 0 V, } V_{\text{IO}} = 1.7 \text{ V} \\ \text{R}_{\text{L}} = 60 \ \Omega, \ \text{C}_{\text{L}} = 100 \text{ pF}, \ \text{C}_{\text{L}(\text{RXD})} = 15 \text{ pF} \\ \text{See Figure 8-4} \end{array} $		180	255	ns	
t _{MODE}	Mode change time, from normal to standby or from standby to normal	See Figure 8-5			20	μs	
t _{WK_FILTER}	Filter time for a valid wake-up pattern	See Figure 9-5	0.5		1.8	μs	
t _{WK_TIMEOUT}	Bus wake-up timeout		0.8		6	ms	
Driver Switchin	g Characteristics	· · · ·					
t _{pHR}	Propagation delay time, high TXD to driver recessive (dominant to recessive)			80		ns	
t _{pLD}	Propagation delay time, low TXD to driver dominant (recessive to dominant)	STB = 0 V R ₁ = 60 Ω, C ₁ = 100 pF		70		ns	
t _{sk(p)}	Pulse skew (tpHR - tpLD)	See Figure 8-2		14		ns	
t _R	Differential output signal rise time	1 [28		ns	
t _F	Differential output signal fall time	1 [50		ns	
t _{TXD_DTO}	Dominant timeout	See Figure 8-6	1.2		4.0	ms	



7.9 Switching Characteristics (continued)

Over recommended operating conditions with $T_J = -40^{\circ}C$ to $150^{\circ}C$ (unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP MAX	UNIT
Receiver Swit	tching Characteristics				
t _{pRH}	Propagation delay time, bus recessive input to high output (dominant to recessive)			81	ns
t _{pDL}	Propagation delay time, bus dominant input to low output (recessive to dominant)	STB = 0 V C _{L(RXD)} = 15 pF — See Figure 8-3		66	ns
t _R	RXD output signal rise time			10	ns
t _F	RXD output signal fall time			10	ns
FD Timing Ch	aracteristics				
t _{BIT(BUS)}	Bit time on CAN bus output pins t _{BIT(TXD)} = 500 ns		450	525	ns
	Bit time on CAN bus output pins t _{BIT(TXD)} = 200 ns	- - 	160	205	ns
	Bit time on CAN bus output pins $t_{BIT(TXD)}$ = 125 ns ⁽¹⁾		85	130	ns
	Bit time on RXD output pins t _{BIT(TXD)} = 500 ns		410	540	ns
t _{BIT(RXD)}	Bit time on RXD output pins t _{BIT(TXD)} = 200 ns	R_L = 60 Ω, C_L = 100 pF, $C_{L(RXD)}$ = 15 pF Δt_{REC} = $t_{BIT(RXD)}$ - $t_{BIT(BUS)}$	130	210	ns
	Bit time on RXD output pins t _{BIT(TXD)} = 125 ns ⁽¹⁾	See Figure 8-4	75	135	ns
	Receiver timing symmetry t _{BIT(TXD)} = 500 ns		-50	20	ns
∆t _{REC}	Receiver timing symmetry t _{BIT(TXD)} = 200 ns		-40	10	ns
	Receiver timing symmetry t _{BIT(TXD)} = 125 ns ⁽¹⁾		-40	10	ns

(1) Measured during characterization and not an ISO 11898-2:2016 parameter.



7.10 Typical Characteristics





8 Parameter Measurement Information





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Figure 8-4. Transmitter and Receiver Timing Test Circuit and Measurement









Figure 8-6. TXD Dominant Timeout Test Circuit and Measurement



Figure 8-7. Driver Short-Circuit Current Test and Measurement



9 Detailed Description

9.1 Overview

The TCAN1044A(V)-Q1 devices meet or exceed the specifications of the ISO 11898-2:2016 high speed CAN (Controller Area Network) physical layer standard. The devices have been certified to the requirements of ISO 11898-2:2016 physical layer requirements according to the GIFT/ICT high speed CAN test specification. The transceivers provide a number of different protection features making them ideal for the stringent automotive system requirements while also supporting CAN FD data rates up to 8 Mbps.

The TCAN1044A(V)-Q1 support the following CAN and CAN FD standards:

- Physical layer:
 - ISO 11898-2:2016 High speed medium access unit
 - ISO 11898-5:2007 High speed medium access unit with low-power mode
 - SAE J2284-1: High Speed CAN (HSC) for Vehicle Applications at 125 kbps
 - SAE J2284-2: High Speed CAN (HSC) for Vehicle Applications at 250 kbps
 - SAE J2284-3: High Speed CAN (HSC) for Vehicle Applications at 500 kbps
 - SAE J2284-4: High-Speed CAN (HSC) for Vehicle Applications at 500 kbps with CAN FD Data at 2 Mbps
 - SAE J2284-5: High-Speed CAN (HSC) for Vehicle Applications at 500 kbps with CAN FD Data at 5 Mbps
- EMC Requirements
 - IEC 62228-3 EMC evaluation of transceivers CAN transceivers
 - VeLIO (Vehicle LAN Interoperability and Optimization) CAN and CAN-FD Transceiver Requirements
 - SAE J2962-2 Communication Transceivers Qualification Requirements CAN
- · Conformance test requirements:
 - ISO 16845-2 Road vehicles Controller area network (CAN) conformance test plan Part 2: High-speed medium access unit conformance test plan



9.2 Functional Block Diagram



Figure 9-1. Block Diagram

9.3 Feature Description

9.3.1 Pin Description

9.3.1.1 TXD

The TXD input is a logic-level signal, referenced to either V_{CC} or V_{IO} from a CAN controller to the transceiver.

9.3.1.2 GND

GND is the ground pin of the transceiver. The pin must be connected to the PCB ground.

9.3.1.3 V_{CC}

 V_{CC} provides the 5-V power supply to the CAN transceiver.

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9.3.1.4 RXD

RXD is the logic-level signal, referenced to either V_{CC} or V_{IO} , from the TCAN1044A-Q1 to a CAN controller. This pin is only driven once V_{IO} is present.

9.3.1.5 V_{IO}

The V_{IO} pin provides the digital I/O voltage to match the CAN controller voltage thus avoiding the requirement for a level shifter. It supports voltages from 1.7 V to 5.5 V providing the widest range of controller support.

9.3.1.6 CANH and CANL

The CANH and CANL pins are the CAN high and CAN low differential bus pins. These pins are internally connected to the CAN transmitter, receiver and the low-power wake-up receiver.

9.3.1.7 STB (Standby)

The STB pin is an input pin used for mode control of the transceiver. The STB pin can be supplied from either the system processor or from a static system voltage source. If normal mode is the only intended mode of operation, the STB pin can be tied directly to GND.

9.3.2 CAN Bus States

The CAN bus has two logical states during operation: recessive and dominant. See Figure 9-2 and Figure 9-3.

A dominant bus state occurs when the bus is driven differentially and corresponds to a logic low on the TXD and RXD pins. A recessive bus state occurs when the bus is biased to $V_{CC}/2$ via the high-resistance internal input resistors (R_{IN}) of the receiver and corresponds to a logic high on the TXD and RXD pins.

A dominant state overwrites the recessive state during arbitration. Multiple CAN nodes may be transmitting a dominant bit at the same time during arbitration, and in this case the differential voltage of the bus is greater than the differential voltage of a single driver.

The TCAN1044A(V)-Q1 transceiver implements a low-power standby (STB) mode which enables a third bus state where the bus pins are weakly biased to ground via the high resistance internal resistors of the receiver. See Figure 9-2 and Figure 9-3.



Figure 9-2. Bus States





A. A - Normal Mode B - Standby Mode

Figure 9-3. Simplified Recessive Common Mode Bias Unit and Receiver

9.3.3 TXD Dominant Timeout (DTO)

During normal mode, the only mode where the CAN driver is active, the TXD DTO circuit prevents the local node from blocking network communication in the event of a hardware or software failure where TXD is held dominant longer than the timeout period t_{TXD_DTO} . The TXD DTO circuit is triggered by a falling edge on TXD. If no rising edge is seen before the timeout period of the circuit, t_{TXD_DTO} , the CAN driver is disabled. This frees the bus for communication between other nodes on the network. The CAN driver is reactivated when a recessive signal is seen on the TXD pin, thus clearing the dominant time out. The receiver remains active and biased to $V_{CC}/2$ and the RXD output reflects the activity on the CAN bus during the TXD DTO fault.

The minimum dominant TXD time allowed by the TXD DTO circuit limits the minimum possible transmitted data rate of the device. The CAN protocol allows a maximum of eleven successive dominant bits (on TXD) for the worst case, where five successive dominant bits are followed immediately by an error frame. The minimum transmitted data rate may be calculated using Equation 1.



Figure 9-4. Example Timing Diagram for TXD Dominant Timeout

9.3.4 CAN Bus short-circuit current limiting

The TCAN1044A(V)-Q1 has several protection features that limit the short-circuit current when a CAN bus line is shorted. These include CAN driver current limiting in the dominant and recessive states and TXD dominant state timeout which prevents permanently having the higher short-circuit current of a dominant state in case of



a system fault. During CAN communication the bus switches between the dominant and recessive states, thus the short-circuit current may be viewed as either the current during each bus state or as a DC average current. When selecting termination resistors or a common-mode choke for the CAN design the average power rating, I_{OS(AVG)}, should be used. The percentage dominant is limited by the TXD DTO and the CAN protocol which has forced state changes and recessive bits due to bit stuffing, control fields, and interframe space. These ensure there is a minimum amount of recessive time on the bus even if the data field contains a high percentage of dominant bits.

The average short-circuit current of the bus depends on the ratio of recessive to dominant bits and their respective short-circuit currents. The average short-circuit current may be calculated using Equation 2.

I_{OS(AVG)} = % Transmit x [(% REC_Bits x I_{OS(SS) REC}) + (% DOM_Bits x I_{OS(SS) DOM})] + [% Receive x I_{OS(SS) REC}] (2)

Where:

- $I_{OS(AVG)}$ is the average short-circuit current
- % Transmit is the percentage the node is transmitting CAN messages
- % Receive is the percentage the node is receiving CAN messages
- % REC Bits is the percentage of recessive bits in the transmitted CAN messages
- % DOM_Bits is the percentage of dominant bits in the transmitted CAN messages
- IOS(SS) REC is the recessive steady state short-circuit current
- IOS(SS) DOM is the dominant steady state short-circuit current

This short circuit current and the possible fault cases of the network should be taken into consideration when sizing the power supply used to generate the transceivers V_{CC} supply.

9.3.5 Thermal Shutdown (TSD)

If the junction temperature of the TCAN1044A(V)-Q1 exceeds the thermal shutdown threshold, T_{TSD}, the device turns off the CAN driver circuitry and blocks the TXD to bus transmission path. The shutdown condition is cleared when the junction temperature of the device drops below T_{TSD} . The CAN bus pins are biased to $V_{CC}/2$ during a TSD fault and the receiver to RXD path remains operational. The TCAN1044A(V)-Q1 TSD circuit includes hysteresis which prevents the CAN driver output from oscillating during a TSD fault.

9.3.6 Undervoltage Lockout

The supply pins, V_{CC} and V_{IO}, have undervoltage detection that places the device into a protected state. This protects the bus during an undervoltage event on either supply pin.

Table 9-1. Undervoltage Lockout - TCAN1044A-Q1						
V _{cc}	DEVICE STATE	BUS	RXD PIN			
> UV _{VCC}	Normal	Per TXD	Mirrors bus			
< UV _{VCC}	Protected	High impedance	High impedance			

Table 9.1 Undervoltage Lockout TCAN1044A O1

< UV _{VCC}		Protected	High impedance	High impedance			
Table 9-2. Undervoltage Lockout - TCAN1044AV-Q1							
Vcc	V _{IO}	DEVICE STATE	BUS	RXD PIN			
> UV _{VCC}	> UV _{VIO}	Normal	Per TXD	Mirrors bus			
< UV _{VCC}	> UV _{VIO}	STB = High: Standby Mode	Weak biased to GND	V _{IO} : Remote wake request See Remote Wake Request via Wake-Up Pattern (WUP) in Standby Mode			
		STB =Low: Protected Mode	High impedance	Recessive			
> UV _{VCC}	< UV _{VIO}	Protected	High impedance	High impedance			

Once the undervoltage condition is cleared and t_{MODE} has expired the TCAN1044A-Q1 will transition to normal mode and the host controller can send and receive CAN traffic again

High impedance

Protected

< UV_{VIO}

< UV_{VCC}

High impedance



9.3.7 Unpowered Device

The TCAN1044A(V)-Q1 is designed to be an ideal passive or no load to the CAN bus if the device is unpowered. The bus pins were designed to have low leakage currents when the device is unpowered, so they do not load the bus. This is critical if some nodes of the network are unpowered while the rest of the of network remains operational.

The logic pins also have low leakage currents when the device is unpowered, so they do not load other circuits which may remain powered.

9.3.8 Floating pins

The TCAN1044A(V)-Q1 has internal pull-ups on critical pins which place the device into known states if the pin floats. This internal bias should not be relied upon by design though, especially in noisy environments, but instead should be considered a failsafe protection feature.

When a CAN controller supporting open-drain outputs is used an adequate external pull-up resistor must be chosen. This ensures that the TXD output of the CAN controller maintains acceptable bit time to the input of the CAN transceiver. See Table 9-3 for details on pin bias conditions.

Pin	Pull-up or Pull-down	Comment								
TXD	Pull-up	Weakly biases TXD towards recessive to prevent bus blockage or TXD DTO triggering								
STB	Pull-up	Weakly biases STB towards low-power standby mode to prevent excessive system power								

Table 9-3. Pin Bias

9.4 Device Functional Modes

9.4.1 Operating Modes

The TCAN1044A(V)-Q1 has two main operating modes; normal mode and standby mode. Operating mode selection is made by applying a high or low level to the STB pin.

STB	Device Mode	Driver	Receiver	RXD Pin							
High	Low current standby mode with bus wake-up	Disabled	Low-power receiver and bus monitor enable	High (recessive) until valid WUP is received See Remote Wake Request via Wake-Up Pattern (WUP) in Standby Mode							
Low	Normal Mode	Enabled	Enabled	Mirrors bus state							

Table 9-4. Operating Modes

9.4.2 Normal Mode

This is the normal operating mode of the TCAN1044A(V)-Q1. The CAN driver and receiver are fully operational and CAN communication is bi-directional.

The driver is translating a digital input on the TXD input to a differential output on the CANH and CANL bus pins.

The receiver is translating the differential signal from CANH and CANL to a digital output on the RXD output.

9.4.3 Standby Mode

This is the low-power mode of the TCAN1044A(V)-Q1. The CAN driver and main receiver are switched off and bi-directional CAN communication is not possible. The low-power receiver and bus monitor circuits are enabled to allow for RXD wake-up requests via the CAN bus. A wake-up request is output to RXD as shown in Figure 9-5. The local CAN protocol controller should monitor RXD for transitions (high-to-low) and reactivate the device to normal mode by pulling the STB pin low. The CAN bus pins are weakly pulled to GND in this mode; see Figure 9-2 and Figure 9-3.

In standby mode, only the V_{IO} supply is required therefore the V_{CC} may be switched off for additional system level current savings.



9.4.3.1 Remote Wake Request via Wake-Up Pattern (WUP) in Standby Mode

The TCAN1044A(V)-Q1 supports a remote wake-up request that is used to indicate to the host controller that the bus is active and the node should return to normal operation.

The device uses the multiple filtered dominant wake-up pattern (WUP) from the ISO 11898-2:2016 standard to qualify bus activity. Once a valid WUP has been received, the wake request is indicated to the controller by a falling edge and low period corresponding to a filtered dominant on the RXD output of the TCAN1044A(V)-Q1.

The WUP consists of a filtered dominant pulse, followed by a filtered recessive pulse, and finally by a second filtered dominant pulse. The first filtered dominant initiates the WUP, and the bus monitor then waits on a filtered recessive; other bus traffic does not reset the bus monitor. Once a filtered recessive is received the bus monitor is waiting for a filtered dominant and again, other bus traffic does not reset the bus monitor. Immediately upon reception of the second filtered dominant the bus monitor recognizes the WUP and drives the RXD output low every time an additional filtered dominant signal is received from the bus.

For a dominant or recessive to be considered filtered, the bus must be in that state for more than the t_{WK_FILTER} time. Due to variability in t_{WK_FILTER} the following scenarios are applicable. Bus state times less than $t_{WK_FILTER(MIN)}$ are never detected as part of a WUP and thus no wake request is generated. Bus state times between $t_{WK_FILTER(MIN)}$ and $t_{WK_FILTER(MAX)}$ may be detected as part of a WUP and a wake-up request may be generated. Bus state times greater than $t_{WK_FILTER(MAX)}$ are always detected as part of a WUP, and thus a wake request is always generated. See Figure 9-5 for the timing diagram of the wake-up pattern.

The pattern and t_{WK_FILTER} time used for the WUP prevents noise and bus stuck dominant faults from causing false wake-up requests while allowing any valid message to initiate a wake-up request.

The ISO 11898-2:2016 standard has defined times for a short and long wake-up filter time. The t_{WK_FILTER} timing for the device has been picked to be within the minimum and maximum values of both filter ranges. This timing has been chosen such that a single bit time at 500 kbps, or two back-to-back bit times at 1 Mbps triggers the filter in either bus state. Any CAN frame at 500 kbps or less would contain a valid WUP.

For an additional layer of robustness and to prevent false wake-ups, the device implements a wake-up timeout feature. For a remote wake-up event to successfully occur, the entire WUP must be received within the timeout value t $\leq t_{WK_TIMEOUT}$. If not, the internal logic is reset and the transceiver remains in its current state without waking up. The full pattern must then be transmitted again, conforming to the constraints mentioned in this section. See Figure 9-5 for the timing diagram of the wake-up pattern with wake timeout feature.







9.4.4 Driver and Receiver Function

The TCAN1044A-Q1 logic I/Os support CMOS levels with respect to either V_{CC} for 5-V systems (TCAN1044A-Q1) or V_{IO} for compatibility with MCUs that support 1.8-V, 2.5-V, 3.3-V, or 5-V systems (TCAN1044AV-Q1).

Table 9-5. Driver Function Table

Device Mode	TXD Input ⁽¹⁾	Bus	Driven Bus State ⁽²⁾	
Device wode		CANH CANL		Driven Bus State
Normal	Low	High	Low	Dominant
Normai	High or open	High impedance	High impedance	Biased recessive
Standby	Х	High impedance	High impedance	Biased to ground

(1) X = irrelevant

(2) For bus state and bias see Figure 9-2 and Figure 9-3

Table 9-6. Receiver Function Table Normal and Standby Mode

Device Mode	CAN Differential Inputs V _{ID} = V _{CANH} – V _{CANL}	Bus State	RXD Pin
	V _{ID} ≥ 0.9 V	Dominant	Low
Normal	0.5 V < V _{ID} < 0.9 V	Undefined	Undefined
	V _{ID} ≤ 0.5 V	Recessive	High
	V _{ID} ≥ 1.15 V	Dominant	High
Standby	0.4 V < V _{ID} < 1.15 V	Undefined	Low if a remote wake event occurred
	V _{ID} ≤ 0.4 V	Recessive	See Figure 9-5
Any	Open (V _{ID} ≈ 0 V)	Open	High



10 Application Information Disclaimer

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

10.1 Application Information

10.2 Typical Application

The TCAN1044A(V)-Q1 transceiver can be used in applications with a host controller or FPGA that includes the link layer portion of the CAN protocol. Figure 10-1 shows a typical configuration for 5-V controller applications. The bus termination is shown for illustrative purposes.



Figure 10-1. Transceiver Application Using 5-V IO Connections

10.2.1 Design Requirements

10.2.1.1 CAN Termination

Termination may be a single $120-\Omega$ resistor at each end of the bus, either on the cable or in a terminating node. If filtering and stabilization of the common-mode voltage of the bus is desired then split termination may be used, see Figure 10-2. Split termination improves the electromagnetic emissions behavior of the network by filtering higher-frequency common-mode noise that may be present on the differential signal lines.





Figure 10-2. CAN Bus Termination Concepts

10.2.2 Detailed Design Procedures

10.2.2.1 Bus Loading, Length and Number of Nodes

A typical CAN application may have a maximum bus length of 40 meters and maximum stub length of 0.3 m. However, with careful design, users can have longer cables, longer stub lengths, and many more nodes to a bus. A high number of nodes requires a transceiver with high input impedance such as the TCAN1044A(V)-Q1

Many CAN organizations and standards have scaled the use of CAN for applications outside the original ISO 11898-2 standard. They made system level trade off decisions for data rate, cable length, and parasitic loading of the bus. Examples of these CAN systems level specifications are ARINC 825, CANopen, DeviceNet, SAE J2284, SAE J1939, and NMEA 2000.

A CAN network system design is a series of tradeoffs. In the ISO 11898-2:2016 specification the driver differential output is specified with a bus load that can range from 50 Ω to 65 Ω where the differential output must be greater than 1.5 V. The TCAN1044A(V)-Q1 family is specified to meet the 1.5-V requirement down to 50 Ω and is specified to meet 1.4-V differential output at 45- Ω bus load. The differential input resistance of the TCAN1044A(V)-Q1 is a minimum of 40 k Ω . If 100 TCAN1044A(V)-Q1 transceivers are in parallel on a bus, this is equivalent to a 400- Ω differential load in parallel with the nominal 60- Ω bus termination which gives a total bus load of approximately 52 Ω . Therefore, the TCAN1044A(V)-Q1 family theoretically supports over 100 transceivers on a single bus segment. However, for a CAN network design margin must be given for signal loss across the system and cabling, parasitic loadings, timing, network imbalances, ground offsets, and signal integrity thus a practical maximum number of nodes is often lower. Bus length may also be extended beyond 40 meters by careful system design and data rate tradeoffs. For example, CANopen network design guidelines allow the network to be up to 1 km with changes in the termination resistance, cabling, less than 64 nodes and significantly lowered data rate.

This flexibility in CAN network design is one of the key strengths of the various extensions and additional standards that have been built on the original ISO 11898-2 CAN standard. However, when using this flexibility the CAN network system designer must take the responsibility of good network design to ensure robust network operation.

Please refer to the application report SLLA270: Controller Area Network Physical layer requirements. This document discusses in detail all system design physical layer parameters.

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Figure 10-3. Typical CAN Bus

10.3 System Examples

The TCAN1044AV-Q1 CAN transceiver is typically used in applications with a host controller or FPGA that includes the link layer portion of the CAN protocol. A 1.8-V, 2.5-V, or 3.3-V application is shown in Figure 10-4. The bus termination is shown for illustrative purposes.



Figure 10-4. Typical Transceiver Application Using 1.8-V, 2.5-V, 3.3-V IO Connections

11 Power Supply Recommendations

The TCAN1044A-Q1 transceiver is designed to operate with a main V_{CC} input voltage supply range between 4.5 V and 5.5 V.

The TCAN1044AV-Q1 implements an IO level shifting supply input, V_{IO} , designed for a range between 1.8 V and 5.5 V.

Both the V_{CC} and V_{IO} inputs must be well regulated. In addition to the power supply filtering a decoupling capacitance, typically 100 nF, should be placed near the CAN transceiver's main V_{CC} and V_{IO} supply pins.



12 Layout

Robust and reliable CAN node design may require special layout techniques depending on the application and design requirements. Since transient disturbances have high frequency content and a wide bandwidth, high-frequency layout techniques should be applied during PCB design.

12.1 Layout Guidelines

- Place the protection and filtering circuitry close to the bus connector, J1, to prevent transients, ESD, and noise from propagating onto the board. This layout example shows a optional transient voltage suppression (TVS) diode, D1, which may be implemented if the system-level requirements exceed the specified rating of the transceiver. This example also shows optional bus filter capacitors C4 and C5.
- Design the bus protection components in the direction of the signal path. Do not force the transient current to divert from the signal path to reach the protection device.
- Decoupling capacitors should be placed as close as possible to the supply pins V_{CC} and V_{IO} of transceiver.
- Use at least two vias for supply and ground connections of bypass capacitors and protection devices to minimize trace and via inductance.

Note

High-frequency current follows the path of least impedance and not the path of least resistance.

This layout example shows how split termination could be implemented on the CAN node. The termination is split into two resistors, R2 and R3, with the center or split tap of the termination connected to ground via capacitor C3. Split termination provides common mode filtering for the bus. See Section 10.2.1.1, Section 9.3.4, and Equation 2 for information on termination concepts and power ratings needed for the termination resistor(s).

12.2 Layout Example



Figure 12-1. Layout Example



13 Device and Documentation Support

13.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

13.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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13.3 Trademarks

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13.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

13.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead finish/	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	Ball material	(3)		(4/5)	
							(6)				
TCAN1044ADDFRQ1	ACTIVE	SOT-23-THIN	DDF	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	2HGF	Samples
TCAN1044ADRBRQ1	ACTIVE	SON	DRB	8	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 150	1044A	Samples
TCAN1044ADRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	1044A	Samples
TCAN1044AVDDFRQ1	ACTIVE	SOT-23-THIN	DDF	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	2HHF	Samples
TCAN1044AVDRBRQ1	ACTIVE	SON	DRB	8	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 150	1044AV	Samples
TCAN1044AVDRQ1	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 150	1044AV	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.



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7-Jan-2022

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Texas

STRUMENTS

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TCAN1044ADDFRQ1	SOT-23- THIN	DDF	8	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TCAN1044ADRBRQ1	SON	DRB	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q1
TCAN1044ADRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TCAN1044AVDDFRQ1	SOT-23- THIN	DDF	8	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TCAN1044AVDRBRQ1	SON	DRB	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q1
TCAN1044AVDRQ1	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1



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PACKAGE MATERIALS INFORMATION

17-Apr-2023



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TCAN1044ADDFRQ1	SOT-23-THIN	DDF	8	3000	210.0	185.0	35.0
TCAN1044ADRBRQ1	SON	DRB	8	3000	367.0	367.0	35.0
TCAN1044ADRQ1	SOIC	D	8	2500	356.0	356.0	35.0
TCAN1044AVDDFRQ1	SOT-23-THIN	DDF	8	3000	210.0	185.0	35.0
TCAN1044AVDRBRQ1	SON	DRB	8	3000	367.0	367.0	35.0
TCAN1044AVDRQ1	SOIC	D	8	2500	356.0	356.0	35.0

DDF0008A



PACKAGE OUTLINE

SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M. 2. This drawing is subject to change without notice. 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.



DDF0008A

EXAMPLE BOARD LAYOUT

SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



4. Publication IPC-7351 may have alternate designs.

5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



DDF0008A

EXAMPLE STENCIL DESIGN

SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

7. Board assembly site may have different recommendations for stencil design.



GENERIC PACKAGE VIEW

VSON - 1 mm max height PLASTIC SMALL OUTLINE - NO LEAD



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4203482/L



DRB0008J

PACKAGE OUTLINE

VSON - 1 mm max height

PLASTIC QUAD FLAT PACK- NO LEAD



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.



DRB0008J

EXAMPLE BOARD LAYOUT

VSON - 1 mm max height

PLASTIC QUAD FLAT PACK- NO LEAD



NOTES: (continued)

- 4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- 5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.



DRB0008J

EXAMPLE STENCIL DESIGN

VSON - 1 mm max height

PLASTIC QUAD FLAT PACK- NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



D0008A



PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



D0008A

EXAMPLE BOARD LAYOUT

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



D0008A

EXAMPLE STENCIL DESIGN

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



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